

NEW PRODUCT**HB56A840B Series**

8,388,608-Word×40-Bit High Density Dynamic RAM Module

- Under development -

Rev.2
May. 22. 1992**Description**

The HB56A840B is a 8M×40 dynamic RAM module, mounted 20 pieces of 16Mbit DRAM (HM5116400J) sealed in SOJ package. An outline of the HB56A840B is 72-pin single in-line package.

Therefore, the HB56A840B makes high density mounting possible without surface mount technology. The HB56A840B provides common data inputs and outputs. Decoupling capacitors are mounted beneath each SOJ only on the one side its module board.

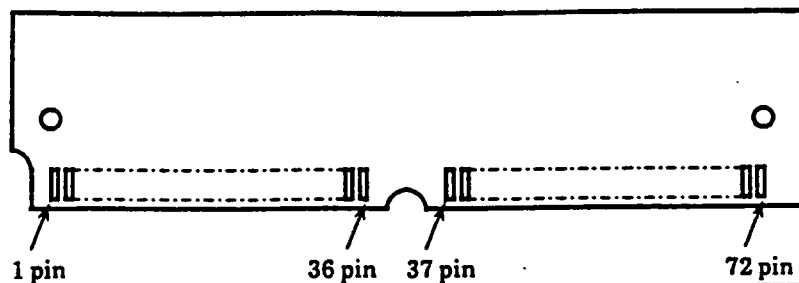
■ Feature

- 72-pin single in-line package
 - Lead pitch 1.27mm
- Single 5V (± 5%) supply
- High speed
 - Access time 60ns / 70ns / 80ns / 100ns (max)
- Low power dissipation
 - Active mode 4.47W / 3.94W / 3.68W / 3.42W (max)
 - Standby mode 210mW (max)
- Fast page mode capability
- 4,096 refresh cycle / 64ms
- 3 variations of refresh
 - $\overline{\text{RAS}}$ only refresh
 - $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh
 - Hidden refresh
- Test function

■ Ordering Information

Part No.	Access time	Package
HB56A840B-6	60ns	72-pin single in-line package
HB56A840B-7	70ns	
HB56A840B-8	80ns	
HB56A840B-10	100ns	

■ Pinout



Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
1	V _{SS}	19	\overline{OE}	37	DQ19	55	DQ28
2	DQ0	20	DQ8	38	DQ20	56	DQ29
3	DQ1	21	DQ9	39	V _{SS}	57	DQ30
4	DQ2	22	DQ10	40	$\overline{CAS0}$	58	DQ31
5	DQ3	23	DQ11	41	A10	59	V _{CC}
6	DQ4	24	DQ12	42	A11	60	DQ32
7	DQ5	25	DQ13	43	$\overline{CAS1}$	61	DQ33
8	DQ6	26	DQ14	44	$\overline{RAS0}$	62	DQ34
9	DQ7	27	DQ15	45	$\overline{RAS1}$	63	DQ35
10	V _{CC}	28	A7	46	DQ21	64	DQ36
11	PD4	29	DQ16	47	\overline{WE}	65	DQ37
12	A0	30	V _{CC}	48	$\times 40 (V_{SS})$	66	DQ38
13	A1	31	A8	49	DQ22	67	PD0
14	A2	32	A9	50	DQ23	68	PD1
15	A3	33	NC	51	DQ24	69	PD2
16	A4	34	NC	52	DQ25	70	PD3
17	A5	35	DQ17	53	DQ26	71	DQ39
18	A6	36	DQ18	54	DQ27	72	V _{SS}

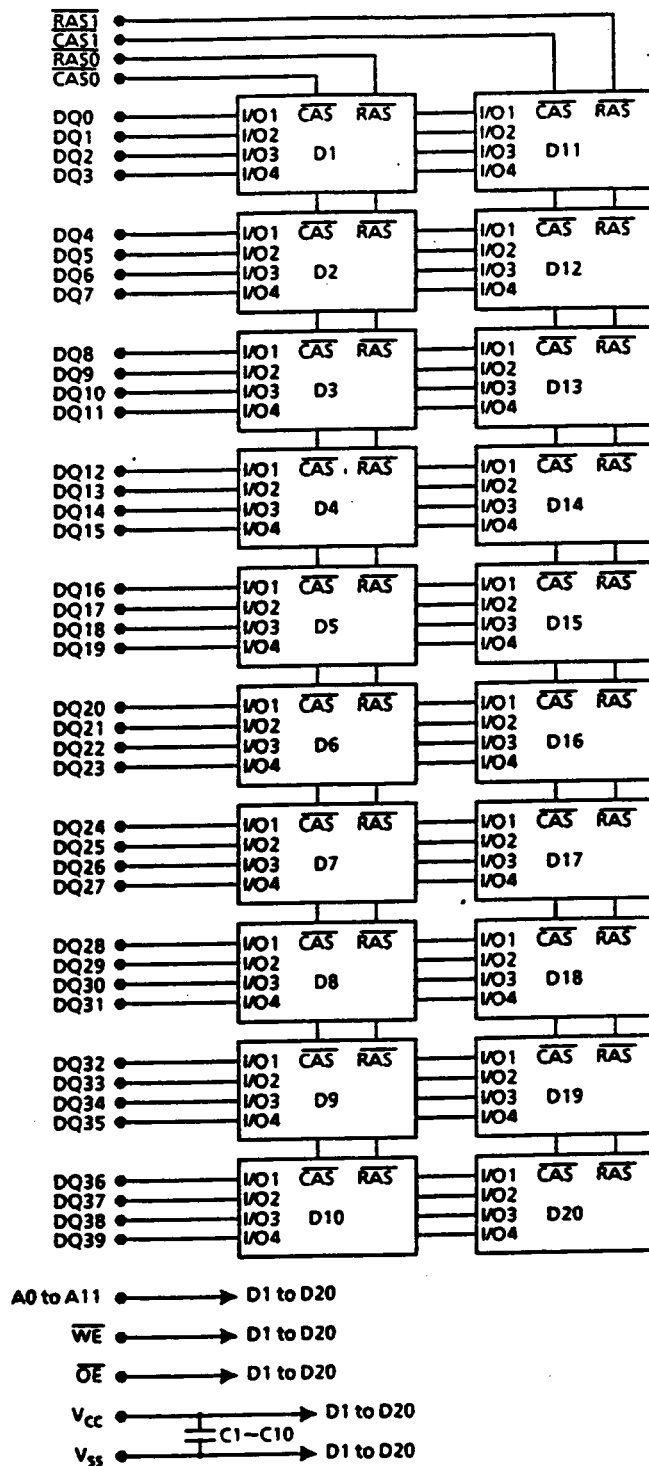
■ Pin Description

Pin Name	Function
A0 – A11	Address Input : A0 – A11 Row Address : A0 – A11 Column Address: A0 – A9 Refresh Address: A0 – A11
DQ0 – DQ39	Data-in / Data-out
$\overline{CAS0}$, $\overline{CAS1}$	Column Address Strobe
$\overline{RAS0}$, $\overline{RAS1}$	Row Address Strobe
\overline{WE}	Read / Write Enable
\overline{OE}	Output Enable
V _{CC}	Power Supply (+5V)
V _{SS}	Ground
PD1 – PD6	Presence Detect Pin
NC	No connection

■ Presence Detect Pin

Pin No.	Pin Name	-6	-7	-8	-10
67	PD0	NC	NC	NC	NC
68	PD1	V _{SS}	V _{SS}	V _{SS}	V _{SS}
69	PD2	NC	V _{SS}	NC	V _{SS}
70	PD3	NC	NC	V _{SS}	V _{SS}
11	PD4	V _{SS}	V _{SS}	V _{SS}	V _{SS}

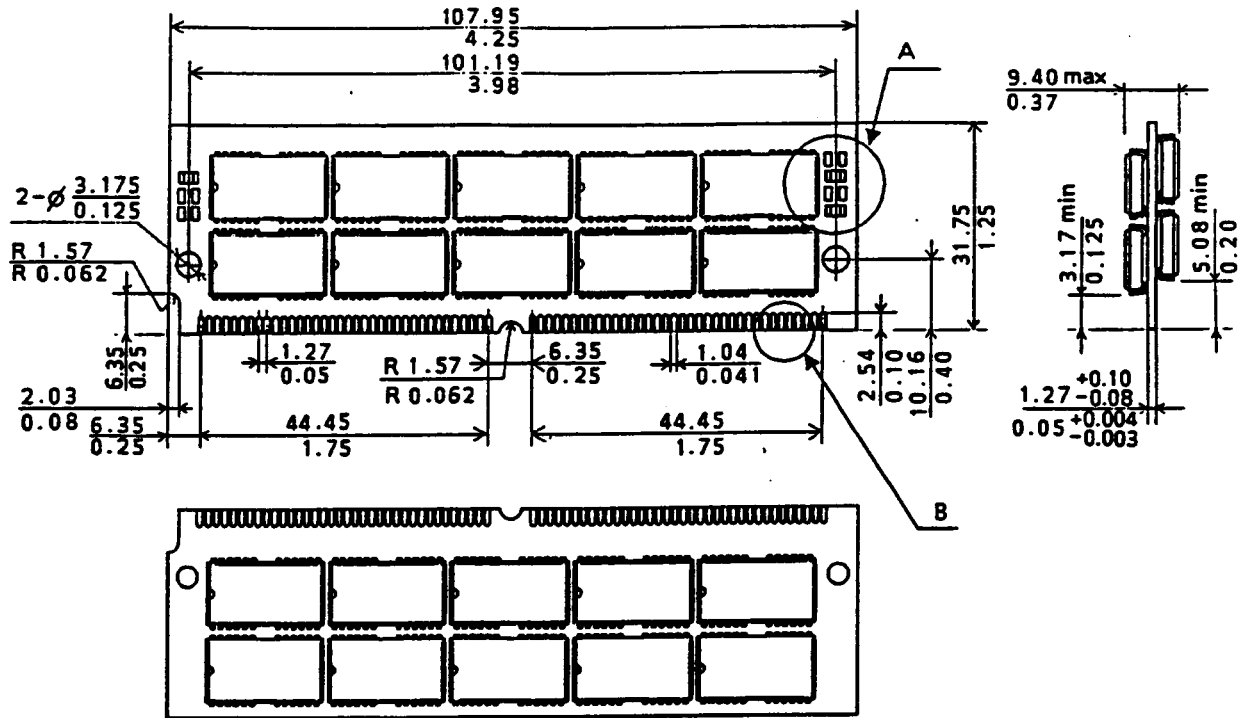
■ Block Diagram



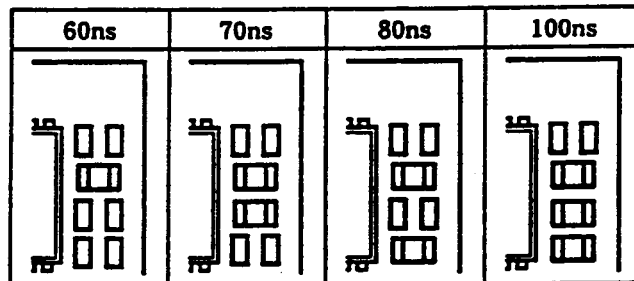
* D1 to D20 : HM5116400J

■ Physical Outline

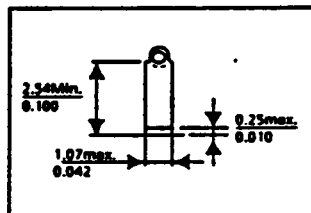
Unit: $\frac{\text{mm}}{\text{inch}}$



Detail A



Detail B



■ Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Voltage on any pin relative to V_{SS}	V_T	-1.0 to +7.0	V
Supply voltage relative to V_{SS}	V_{CC}	-1.0 to +7.0	V
Short circuit output current	I_{out}	50	mA
Power dissipation	P_T	10	W
Operating temperature	T_{opr}	0 to +70	°C
Storage temperature	T_{stg}	-55 to +125	°C

■ Electrical Characteristics

☆ Recommended DC Operating Conditions ($T_a = 0$ to $+70^\circ\text{C}$)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Note
Supply voltage	V_{CC}	4.75	5.0	5.25	V	1
Input high voltage	V_{IH}	2.4	-	5.5	V	1
Input low voltage	V_{IL}	-1.0	-	0.8	V	1

Note : 1. All voltage referenced to V_{SS}

☆ DC Electrical Characteristics (Ta=0 to +70°C, VCC=5V±5%, VSS=0V)

Parameter	Symbol	-6		-7		-8		-10		Unit	Test Condition	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.			
Operating current	ICC1	-	850	-	750	-	700	-	650	mA	t _{RC} =min	1,2
Standby current	ICC2	-	40	-	40	-	40	-	40	mA	TTL interface RAS, CAS = V _{III} D _{out} = High-Z	
		-	20	-	20	-	20	-	20	mA	CMOS interface RAS, CAS ≥ V _{CC} - 0.2V D _{out} = High-Z	
RAS-only refresh current	ICC3	-	850	-	750	-	700	-	650	mA	t _{RC} =min	2
Standby current	ICC5	-	100	-	100	-	100	-	100	mA	RAS = V _{IH} CAS = V _{IL} D _{out} = enable	1
CAS-before-RAS refresh current	ICC6	-	850	-	750	-	700	-	650	mA	t _{RC} =min	
Page mode current	ICC7	-	950	-	850	-	800	-	750	mA	t _{PC} =min	1,3
Input leakage current	I _{LI}	-10	10	-10	10	-10	10	-10	10	μA	0V ≤ V _{in} ≤ 7V	
Output leakage current	I _{LO}	-10	10	-10	10	-10	10	-10	10	μA	0V ≤ V _{out} ≤ 7V D _{OUT} = disable	
Output high voltage	V _{OH}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	2.4	V _{CC}	V	High I _{out} = -5mA	
Output low voltage	V _{OL}	0	0.4	0	0.4	0	0.4	0	0.4	V	Low I _{out} = 4.2mA	

Notes : 1. I_{CC} depends on output load condition when the device is selected, I_{CC} max is specified at the output open condition.

2. Address can be changed once or less while $\overline{\text{RAS}} = V_{\text{IL}}$.

3. Address can be changed once or less while $\overline{\text{CAS}} = V_{\text{IH}}$.

☆ Capacitance ($T_a = 25^\circ\text{C}$, $V_{CC} = 5V \pm 5\%$)

Parameter	Symbol	Typ.	Max.	Unit	Note
Input capacitance (Address)	C_{11}	—	140	pF	1
Input capacitance (\overline{WE} , \overline{OE})	C_{12}	—	160	pF	1
Input capacitance (\overline{RAS} , \overline{CAS})	C_{13}	—	90	pF	1
Output capacitance (DQ)	$C_{1/O1}$	—	25	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.
2. $\overline{CAS} = V_{IH}$ to disable D_{out} .

☆ AC Characteristics ($T_a = 0$ to 70°C , $V_{CC} = 5V \pm 5\%$, $V_{SS} = 0V$) 1), 2), 3), 19), 20)

● Read, Write and Refresh Cycle (Common parameters)

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Random read or write cycle time	t_{RC}	110	—	130	—	150	—	180	—	ns	
\overline{RAS} precharge time	t_{RP}	40	—	50	—	60	—	70	—	ns	
\overline{CAS} precharge time	t_{CP}	10	—	10	—	10	—	10	—	ns	
\overline{RAS} pulse width	t_{RAS}	60	10000	70	10000	80	10000	100	10000	ns	
\overline{CAS} pulse width	t_{CAS}	15	10000	18	10000	20	10000	25	10000	ns	
Row address setup time	t_{ASR}	0	—	0	—	0	—	0	—	ns	
Row address hold time	t_{RAH}	10	—	10	—	10	—	10	—	ns	
Column address setup time	t_{ASC}	0	—	0	—	0	—	0	—	ns	
Column address hold time	t_{CAH}	15	—	15	—	15	—	15	—	ns	
\overline{RAS} to \overline{CAS} delay time	t_{RCD}	20	45	20	52	20	60	20	75	ns	4
\overline{RAS} to column address delay time	t_{RAD}	15	30	15	35	15	40	15	55	ns	5
\overline{RAS} hold time	t_{RSH}	15	—	18	—	20	—	25	—	ns	
\overline{CAS} hold time	t_{CSH}	60	—	70	—	80	—	100	—	ns	
\overline{CAS} to \overline{RAS} precharge time	t_{CRP}	5	—	5	—	5	—	5	—	ns	
\overline{OE} to D_{in} delay time	t_{OED}	15	—	18	—	20	—	25	—	ns	6
\overline{OE} delay time from D_{in}	t_{DZO}	0	—	0	—	0	—	0	—	ns	7
\overline{CAS} delay time from D_{in}	t_{DZC}	0	—	0	—	0	—	0	—	ns	7
Transition time (rise and fall)	t_T	3	30	3	30	3	30	3	30	ns	8
Refresh period	t_{REF}	—	64	—	64	—	64	—	64	ms	22

• Read Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Access time from $\overline{\text{RAS}}$	t_{RAC}	–	60	–	70	–	80	–	100	ns	9,10,21
Access time from $\overline{\text{CAS}}$	t_{CAC}	–	15	–	18	–	20	–	25	ns	10,11, 18,21
Access time from address	t_{AA}	–	30	–	35	–	40	–	45	ns	10,12, 18,21
Access time from $\overline{\text{OE}}$	t_{OEA}	–	15	–	18	–	20	–	25	ns	10,21
Read command setup time	t_{RCS}	0	–	0	–	0	–	0	–	ns	
Read command hold time to $\overline{\text{CAS}}$	t_{RCH}	0	–	0	–	0	–	0	–	ns	13
Read command hold time to $\overline{\text{RAS}}$	t_{RRH}	5	–	5	–	5	–	5	–	ns	13
Column address to $\overline{\text{RAS}}$ lead time	t_{RAL}	30	–	35	–	40	–	45	–	ns	
Column address to $\overline{\text{CAS}}$ lead time	t_{CAL}	30	–	35	–	40	–	45	–	ns	
$\overline{\text{CAS}}$ to output in low-Z	t_{CLZ}	0	–	0	–	0	–	0	–	ns	
Output data hold time	t_{OH}	3	–	3	–	3	–	3	–	ns	
Output data hold time from $\overline{\text{OE}}$	t_{OHO}	3	–	3	–	3	–	3	–	ns	
Output buffer turn-off time	t_{OFF}	–	15	–	18	–	20	–	25	ns	14
Output buffer turn-off to $\overline{\text{OE}}$	t_{OEZ}	–	15	–	18	–	20	–	25	ns	14
$\overline{\text{CAS}}$ to Din delay time	t_{CDD}	15	–	18	–	20	–	25	–	ns	6

• Write Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Write command setup time	t_{WCS}	0	–	0	–	0	–	0	–	ns	15
Write command hold time	t_{WCH}	15	–	15	–	15	–	15	–	ns	
Write command pulse width	t_{WP}	15	–	15	–	15	–	15	–	ns	
Write command to $\overline{\text{RAS}}$ lead time	t_{RWL}	15	–	18	–	20	–	25	–	ns	
Write command to $\overline{\text{CAS}}$ lead time	t_{CWL}	15	–	18	–	20	–	25	–	ns	
Data-in setup time	t_{DS}	0	–	0	–	0	–	0	–	ns	16
Data-in hold time	t_{DIH}	15	–	15	–	15	–	15	–	ns	16

• Read-Modify-Write Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Read-modify-write cycle time	t _{RWC}	155	—	181	—	205	—	245	—	ns	
$\overline{\text{RAS}}$ to $\overline{\text{WE}}$ delay time	t _{RWD}	85	—	98	—	110	—	135	—	ns	15
$\overline{\text{CAS}}$ to $\overline{\text{WE}}$ delay time	t _{CWD}	40	—	46	—	50	—	60	—	ns	15
Column address to $\overline{\text{WE}}$ delay time	t _{AWD}	55	—	63	—	70	—	80	—	ns	15
$\overline{\text{OE}}$ hold time from $\overline{\text{WE}}$	t _{OEH}	15	—	18	—	20	—	25	—	ns	

• Refresh Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
CAS setup time (CBR refresh cycle)	t _{CSR}	10	—	10	—	10	—	10	—	ns	
CAS hold time (CBR refresh cycle)	t _{CHR}	20	—	20	—	20	—	20	—	ns	
WE setup time (CBR refresh cycle)	t _{WRP}	10	—	10	—	10	—	10	—	ns	
WE hold time (CBR refresh cycle)	t _{WRH}	10	—	10	—	10	—	10	—	ns	
RAS precharge to CAS hold time	t _{RPC}	0	—	0	—	0	—	0	—	ns	

• Fast Page Mode Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Fast page mode cycle time	t _{PC}	40	—	45	—	50	—	55	—	ns	
Fast page mode RAS pulse width	t _{RASP}	—	100000	—	100000	—	100000	—	100000	ns	17
Access time from CAS precharge	t _{CPA}	—	35	—	40	—	45	—	50	ns	10,18,21
RAS hold time from CAS precharge	t _{CPRH}	35	—	40	—	45	—	50	—	ns	

● Fast Page Mode Read-Modify-Write Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Fast page mode read-modify-write cycle time	t _{PRWC}	85	—	96	—	105	—	120	—	ns	
WE delay time from CAS precharge	t _{CPW}	60	—	68	—	75	—	85	—	ns	15

● Test Mode Cycle *20)

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Test mode \overline{WE} setup time	t _{WTS}	10	—	10	—	10	—	10	—	ns	
Test mode \overline{WE} hold time	t _{WTH}	10	—	10	—	10	—	10	—	ns	

● Counter Test Cycle

Parameter	Symbol	-6		-7		-8		-10		Unit	Note
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
CAS precharge time in counter test cycle	t _{CPT}	40	—	40	—	40	—	50	—	ns	

Notes

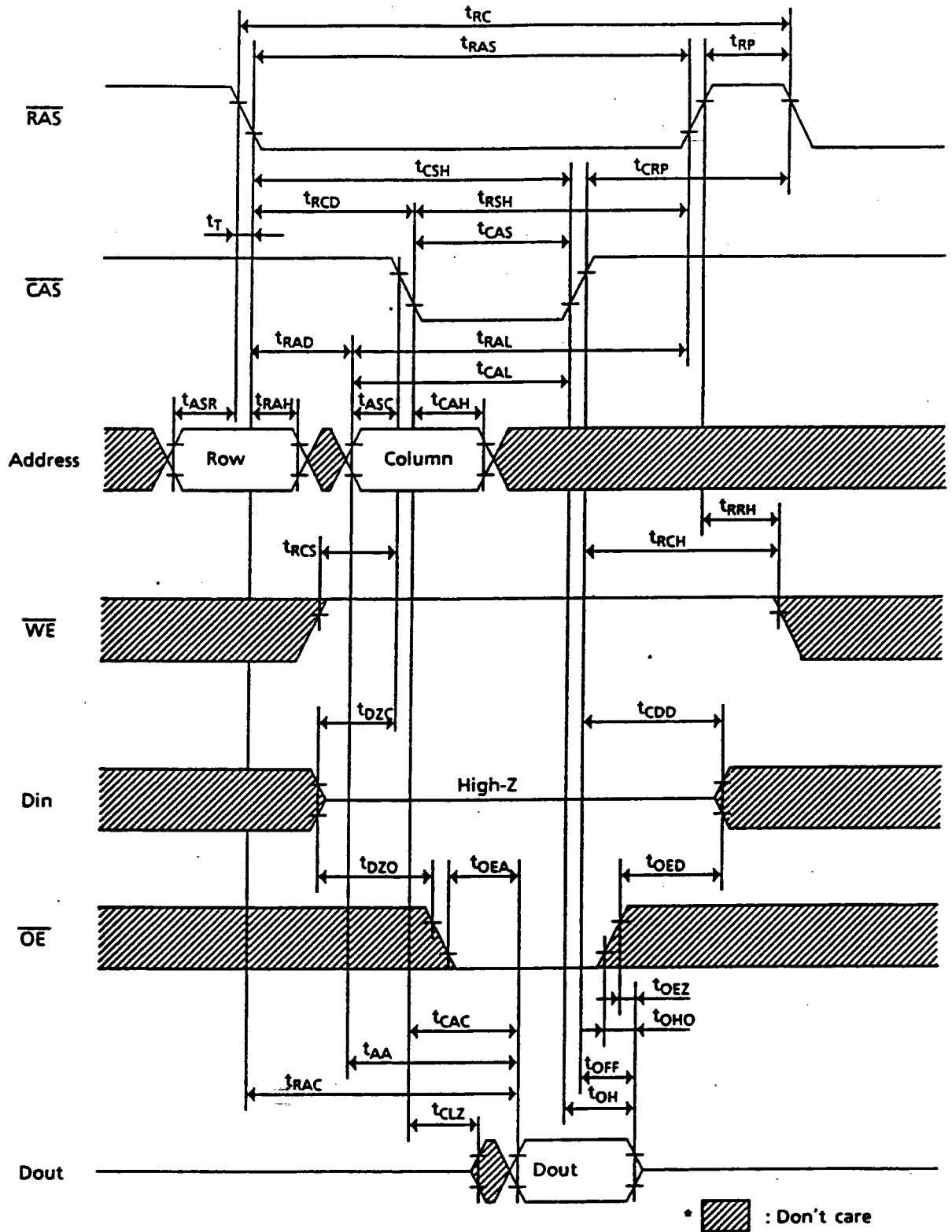
1. AC measurements assume $t_T = 5\text{ns}$.
2. An initial pause of $100\mu\text{s}$ is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing $\overline{\text{RAS}}$ -only refresh or $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh). If the internal refresh counter is used, a minimum of eight $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$ refresh cycles are required.
3. Only row address is indispensable on address A10 and A11.
4. Operation with the $t_{\text{RCD}}(\text{max})$ limit insures that $t_{\text{RAC}}(\text{max})$ can be met, $t_{\text{RCD}}(\text{max})$ is specified as a reference point only; if t_{RCD} is greater than the specified $t_{\text{RCD}}(\text{max})$ limit, then access time is controlled exclusively by t_{CAC} .
5. Operation with the $t_{\text{RAD}}(\text{max})$ limit insures that $t_{\text{RAC}}(\text{max})$ can be met, $t_{\text{RAD}}(\text{max})$ is specified as a reference point only; if t_{RAD} is greater than the specified $t_{\text{RAD}}(\text{max})$ limit, then access time is controlled exclusively by t_{AA} .
6. Either t_{OED} or t_{CDD} must be satisfied.
7. Either t_{DZO} or t_{DZC} must be satisfied.
8. $V_{\text{IH}}(\text{min})$ and $V_{\text{IL}}(\text{max})$ are reference levels for measuring timing of input signals. Also, transition times are measured between $V_{\text{IH}}(\text{min})$ and $V_{\text{IL}}(\text{max})$.
9. Assumes that $t_{\text{RCD}} < t_{\text{RCD}}(\text{max})$ and $t_{\text{RAD}} < t_{\text{RAD}}(\text{max})$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
10. Measured with a load circuit equivalent to 2TTL loads and 100pF .
11. Assumes that $t_{\text{RCD}} \geq t_{\text{RCD}}(\text{max})$ and $t_{\text{RAD}} \leq t_{\text{RAD}}(\text{max})$.
12. Assumes that $t_{\text{RCD}} \leq t_{\text{RCD}}(\text{max})$ and $t_{\text{RAD}} \geq t_{\text{RAD}}(\text{max})$.
13. Either t_{RCH} or t_{RRH} must be satisfied for a read cycles.
14. $t_{\text{OFF}}(\text{max})$ and $t_{\text{OEZ}}(\text{max})$ is define the time at which the output achieve the open circuit condition and are not referenced to output voltage levels.
15. t_{WCS} , t_{RWD} , t_{CWD} , t_{AWD} and t_{CPW} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only; if $t_{\text{WCS}} \geq t_{\text{WCS}}(\text{min})$, the cycle is an early write cycle and data out pin will remain open circuit (high impedance) throughout the entire cycle; if $t_{\text{RWD}} \geq t_{\text{RWD}}(\text{min})$, $t_{\text{CWD}} \geq t_{\text{CWD}}(\text{min})$ and $t_{\text{AWD}} \geq t_{\text{AWD}}(\text{min})$, or $t_{\text{CWD}} \geq t_{\text{CWD}}(\text{min})$, $t_{\text{AWD}} \geq t_{\text{AWD}}(\text{min})$ and $t_{\text{CPW}} \geq t_{\text{CPW}}(\text{min})$ the cycle is a read-modify-write and the data output will contain data read from the selected cell; if neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminated.
16. These parameters are referenced to $\overline{\text{CAS}}$ leading edge in early write cycles and to $\overline{\text{WE}}$ leading edge in delayed write or read-modify-write cycles.
17. t_{RASP} defines $\overline{\text{RAS}}$ pulse width in fast page mode cycles.
18. Access time is determined by the longer of t_{AA} or t_{CAC} or t_{CPA} .
19. In delayed write or read-modify-write cycles, $\overline{\text{OE}}$ must disable output buffer prior to applying data to the device. After $\overline{\text{RAS}}$ is reset, if $t_{\text{OEH}} \geq t_{\text{CWL}}$, the I/O pins will remain open circuit (high impedance); if $t_{\text{OEH}} < t_{\text{CWL}}$, invalid data will be out at each I/O.

Notes (Continued):

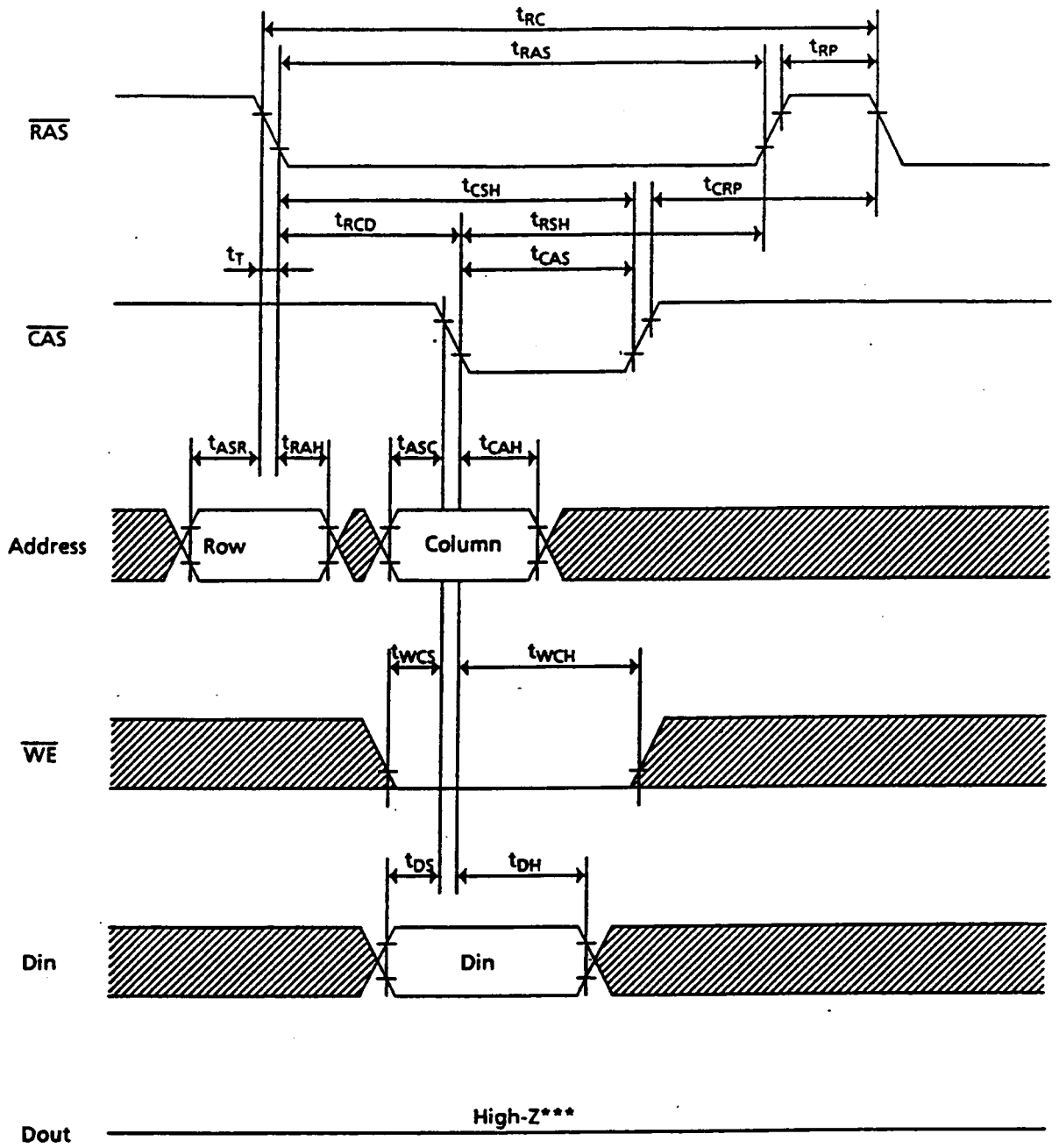
20. The 16M DRAM offers a 16-bits time saving parallel test mode. Address CA0 and CA1 for the $4M \times 4$ are don't care during test mode. Test mode is set by performing a \overline{WE} -and- \overline{CAS} -before- \overline{RAS} (WCBR) cycle. In 16-bits parallel test mode, data is written into 4 bits in parallel at each I/O and read out from each I/O. If 4 bits of each I/O are equal (all 1s or 0s), data output pin is a high state during test mode read cycle, then the device has passed. If they are not equal, data output pin is a low state, then the device has failed. Refresh during test mode operation can be performed by normal read cycles or by WCBR refresh cycles. To get out of test mode and enter a normal operation mode, perform either a regular \overline{CAS} -before- \overline{RAS} refresh cycle or \overline{RAS} -only refresh cycle.
21. In a test mode read cycle, the value of t_{RAC} , t_{AA} , t_{CAC} and t_{CPA} is delayed by 2ns to 5ns for the specified value. These parameters should be specified in test mode cycles by adding the above value to the specified value in this data sheet.
22. t_{REF} is determined by 4,096 refresh cycles.

■ Timing Waveform

Read Cycle

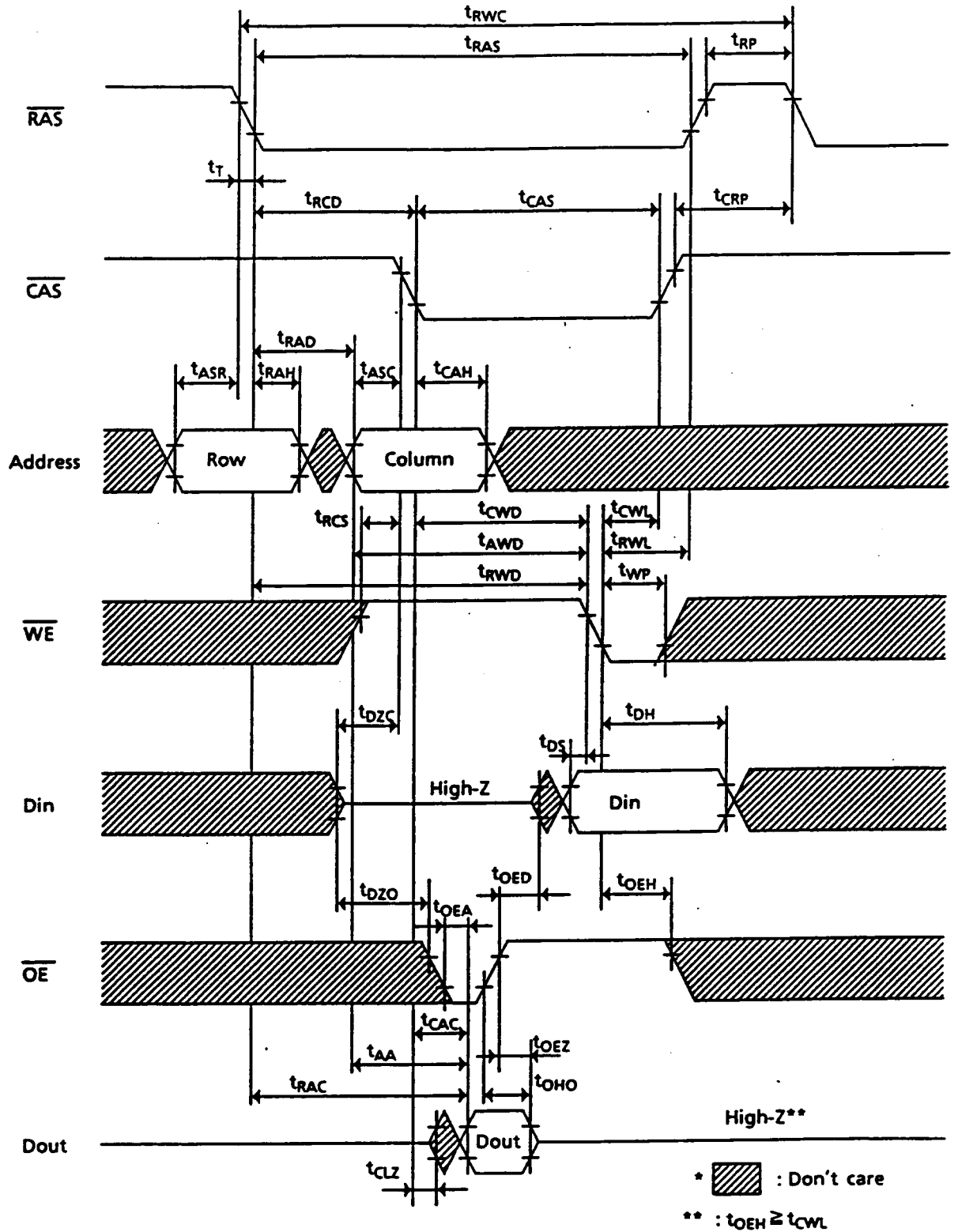


Early Write Cycle

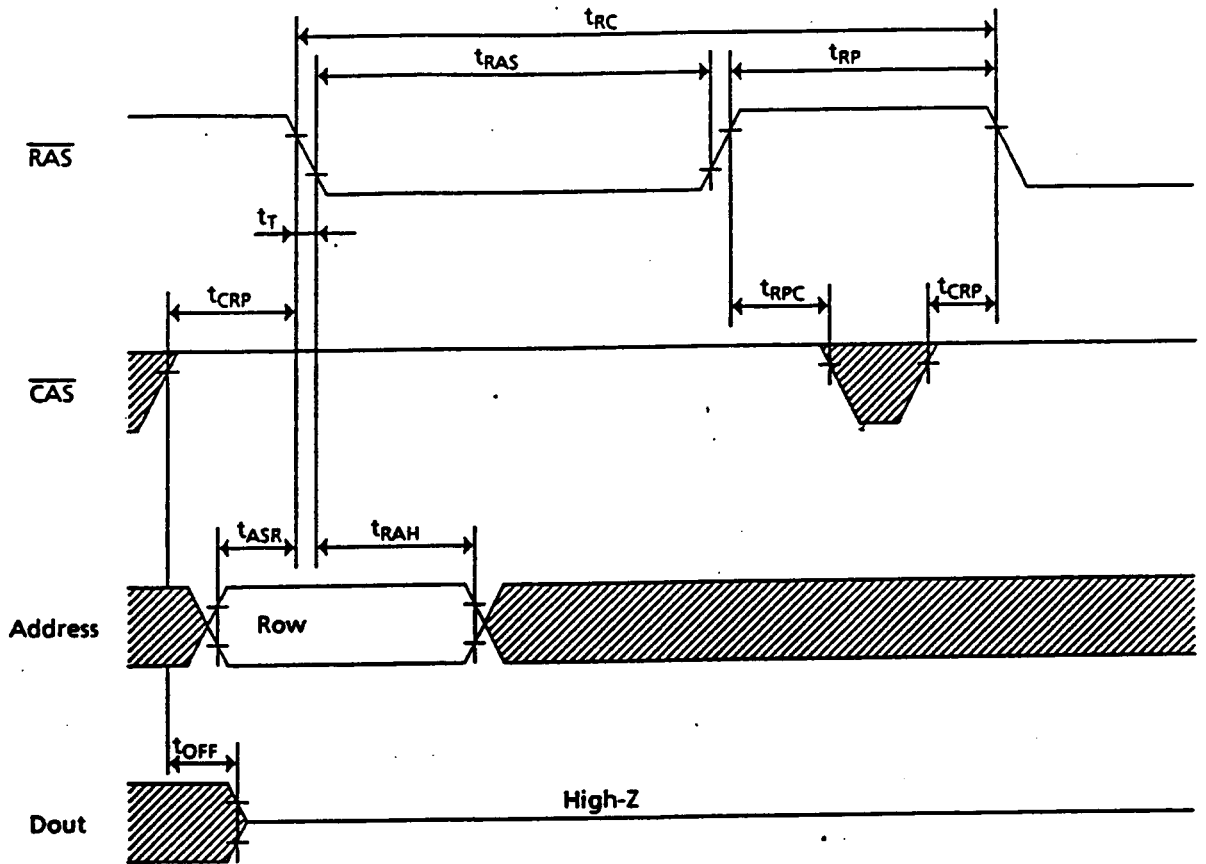


- * \overline{OE} : Don't care
- ** : Don't care
- *** $t_{wcs} \geq t_{wcs}(\text{min})$

Read-Modify-Write Cycle *19

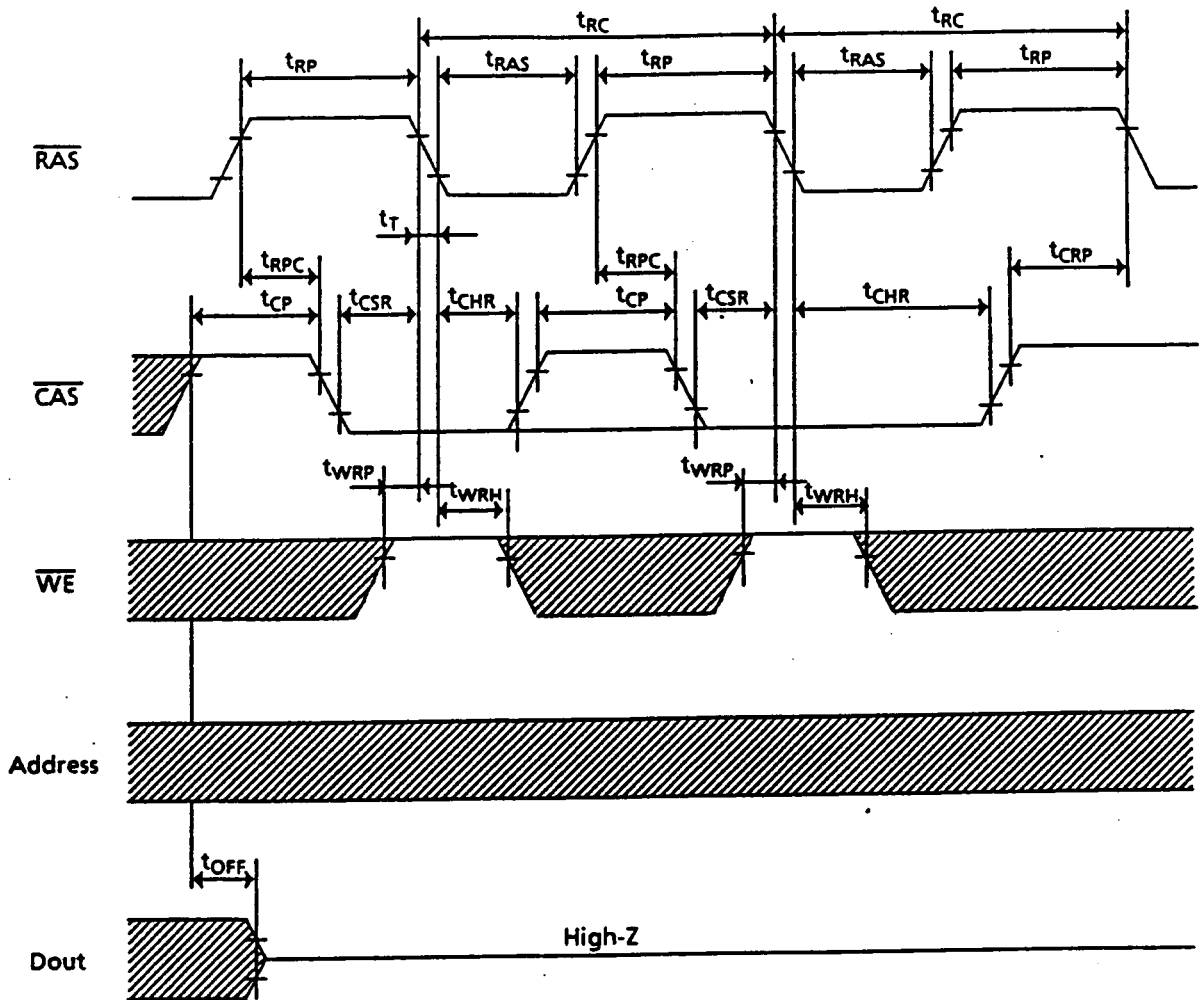


$\overline{\text{RAS}}$ -Only Refresh Cycle



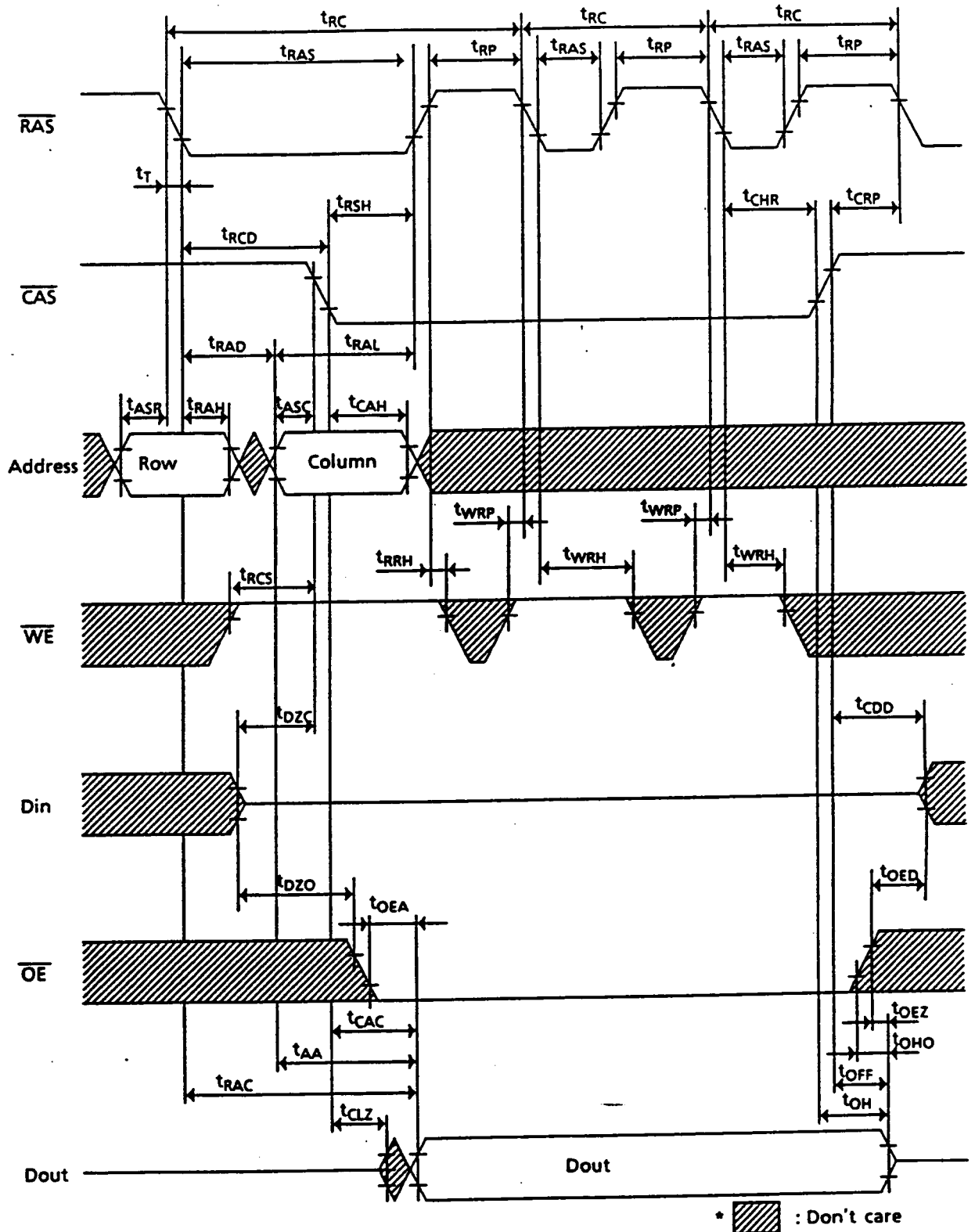
- * $\overline{\text{OE}}, \overline{\text{WE}}$: Don't care
- ** : Don't care
- *** Refresh address : A0 - A11 (RA0 - RA11)

CAS-Before-RAS Refresh Cycle

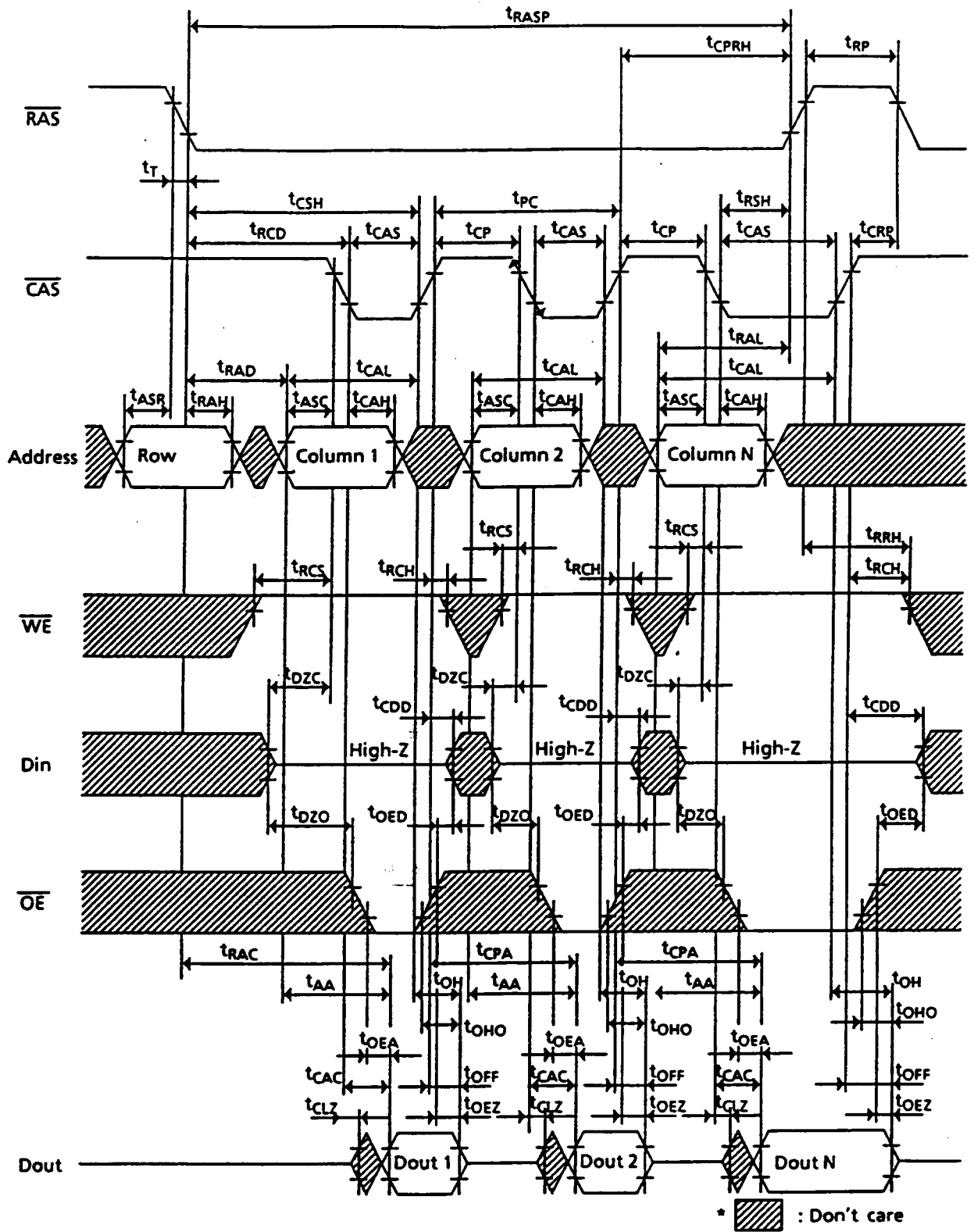


- * \overline{OE} : Don't care
- ** : Don't care

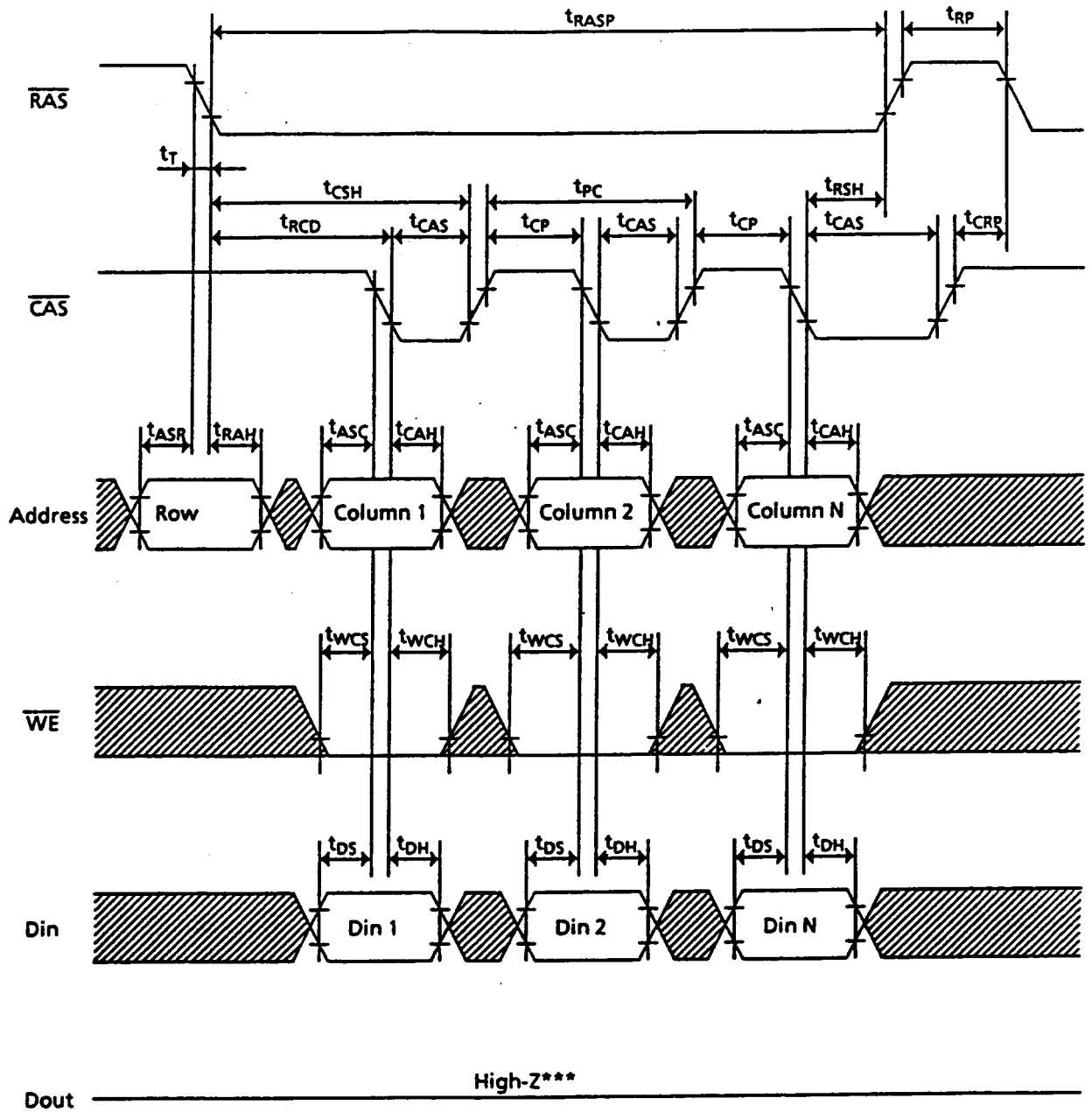
Hidden Refresh Cycle



Fast Page Mode Read Cycle

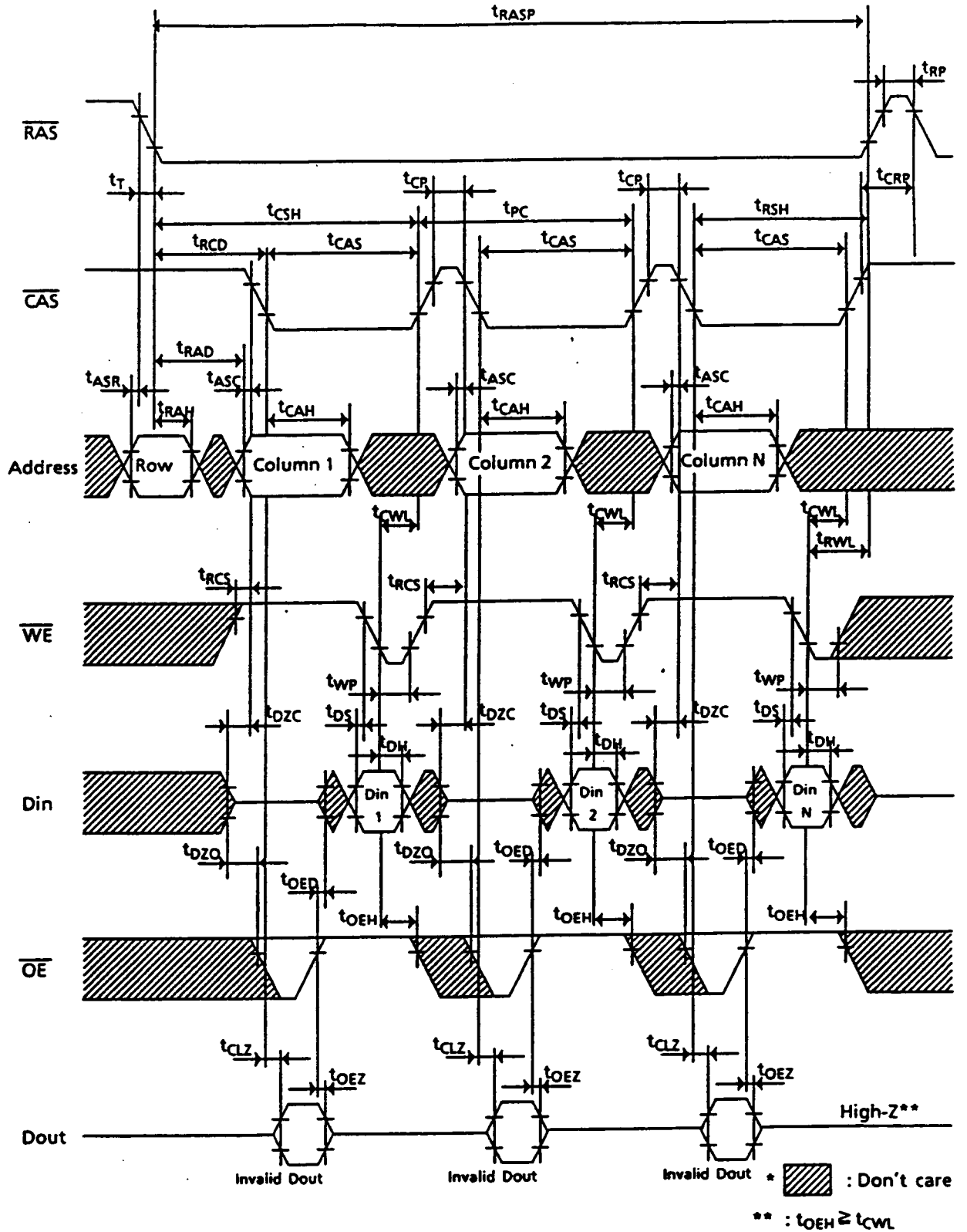


Fast Page Mode Early Write Cycle

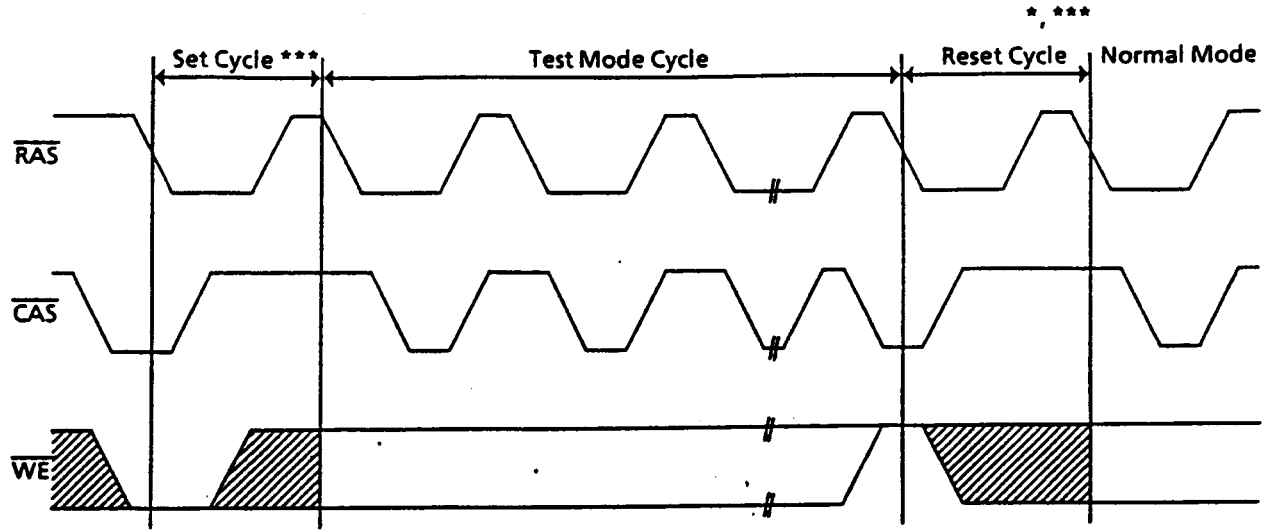


- * \overline{OE} : Don't care
- ** : Don't care
- *** $t_{WCS} \geq t_{WCS}(\text{min})$

Fast Page Mode Delayed Write Cycle *19

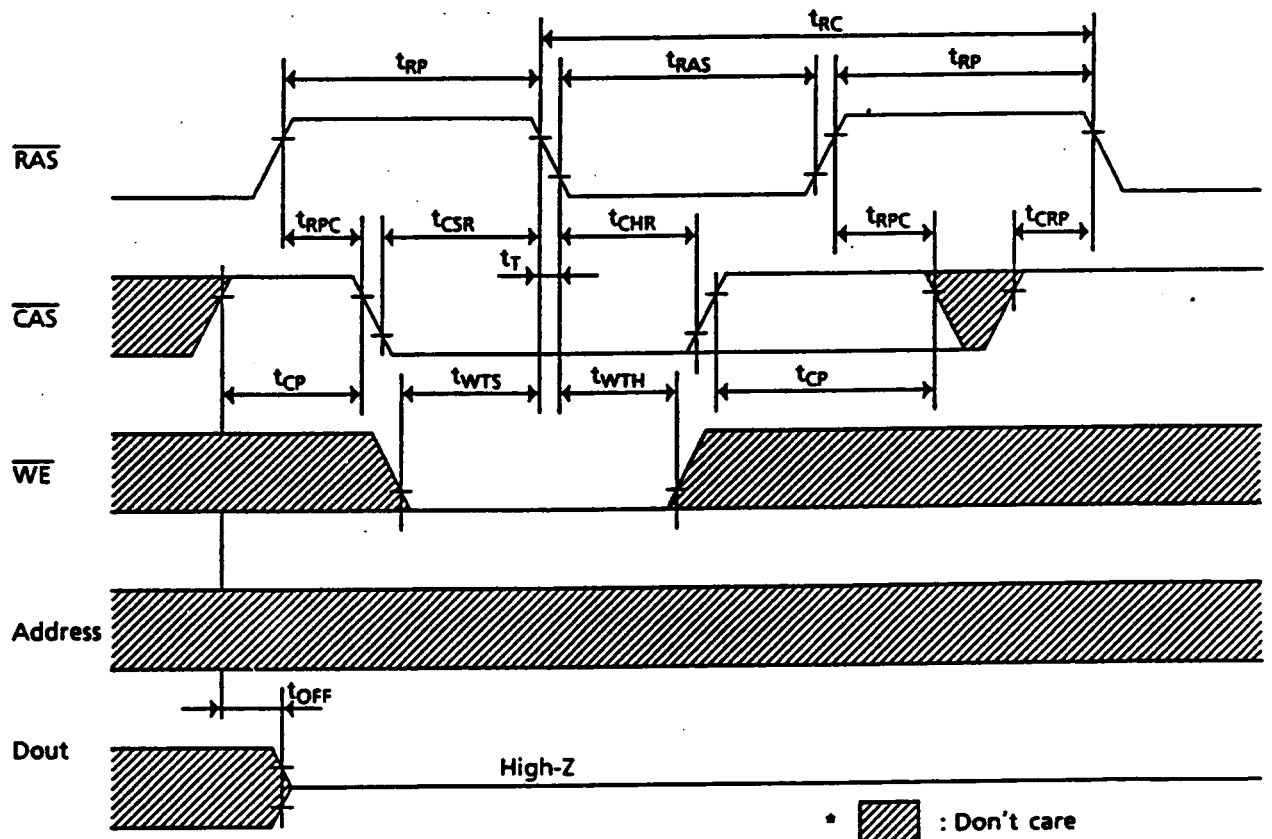


Test Mode Cycle *20



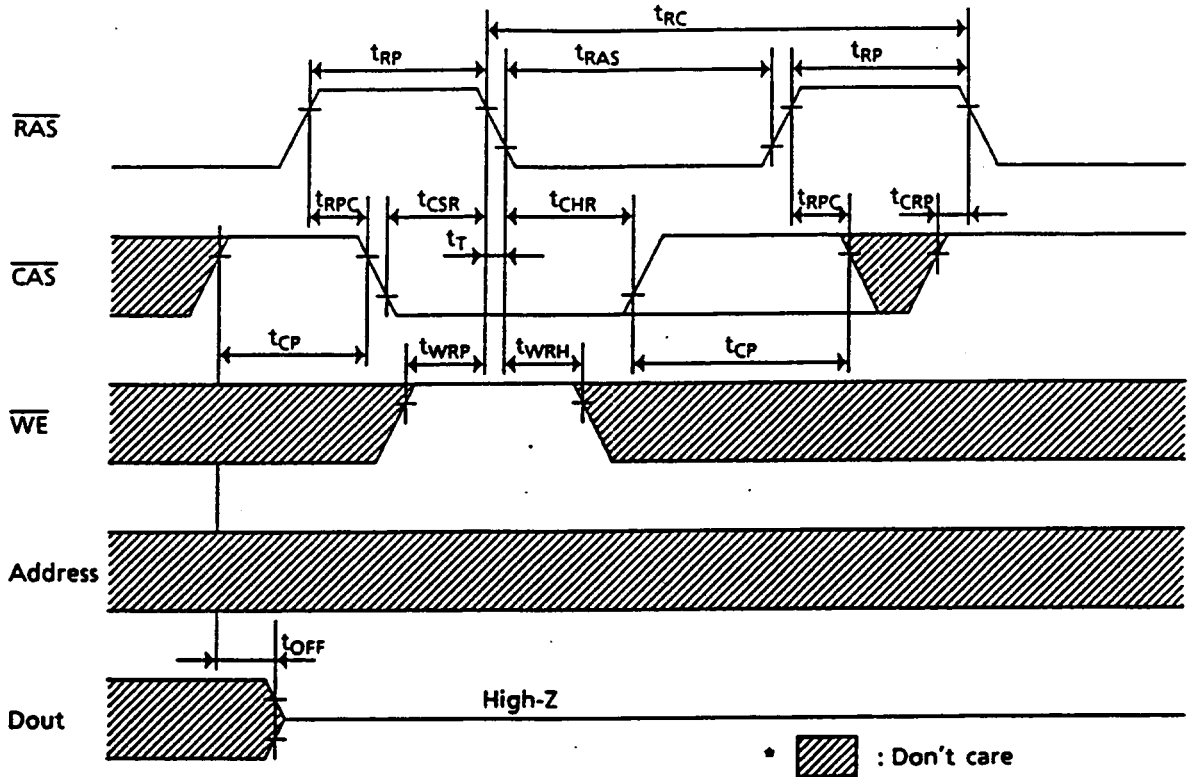
- * CBR or \overline{RAS} only refresh
- ** : Don't care
- *** Address, Din, \overline{OE} : Don't care

Test Mode Set Cycle

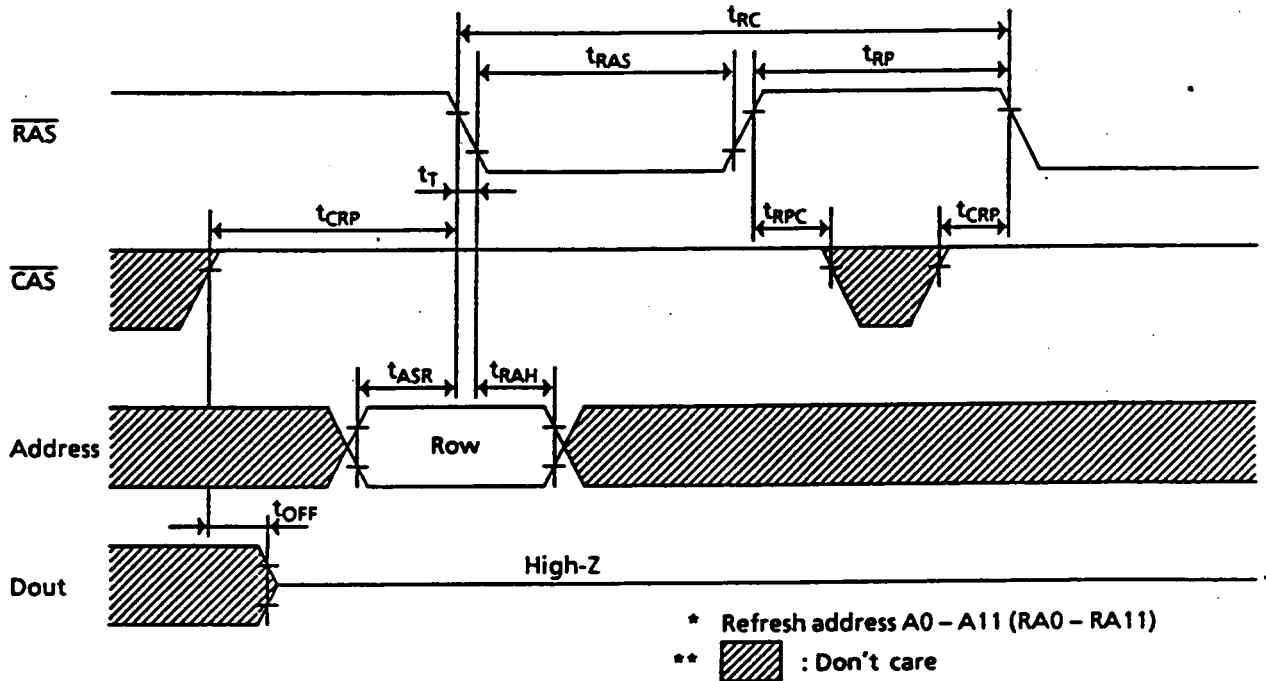


- * : Don't care

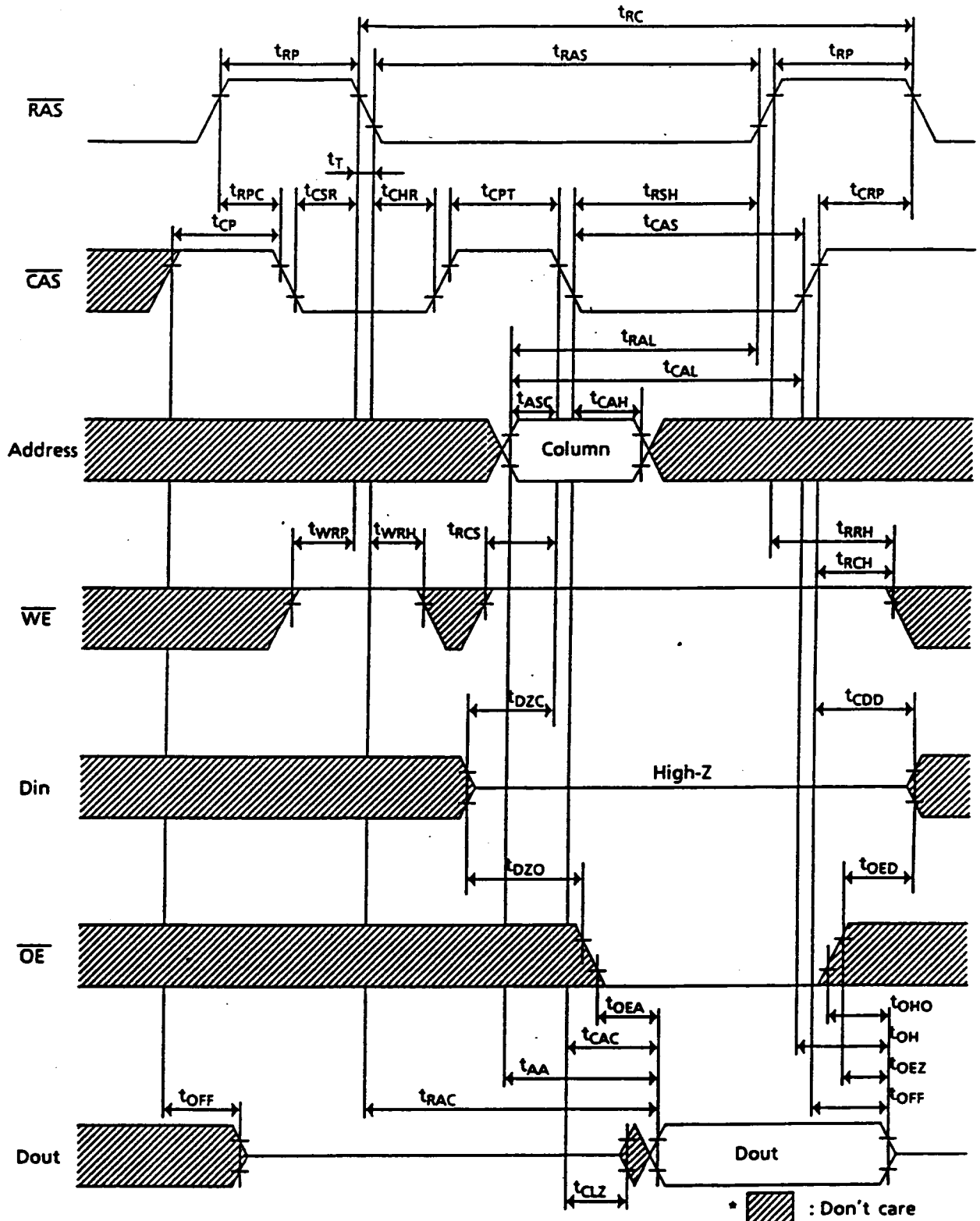
Test Mode Reset Cycle
 CAS-Before-RAS Refresh Cycle



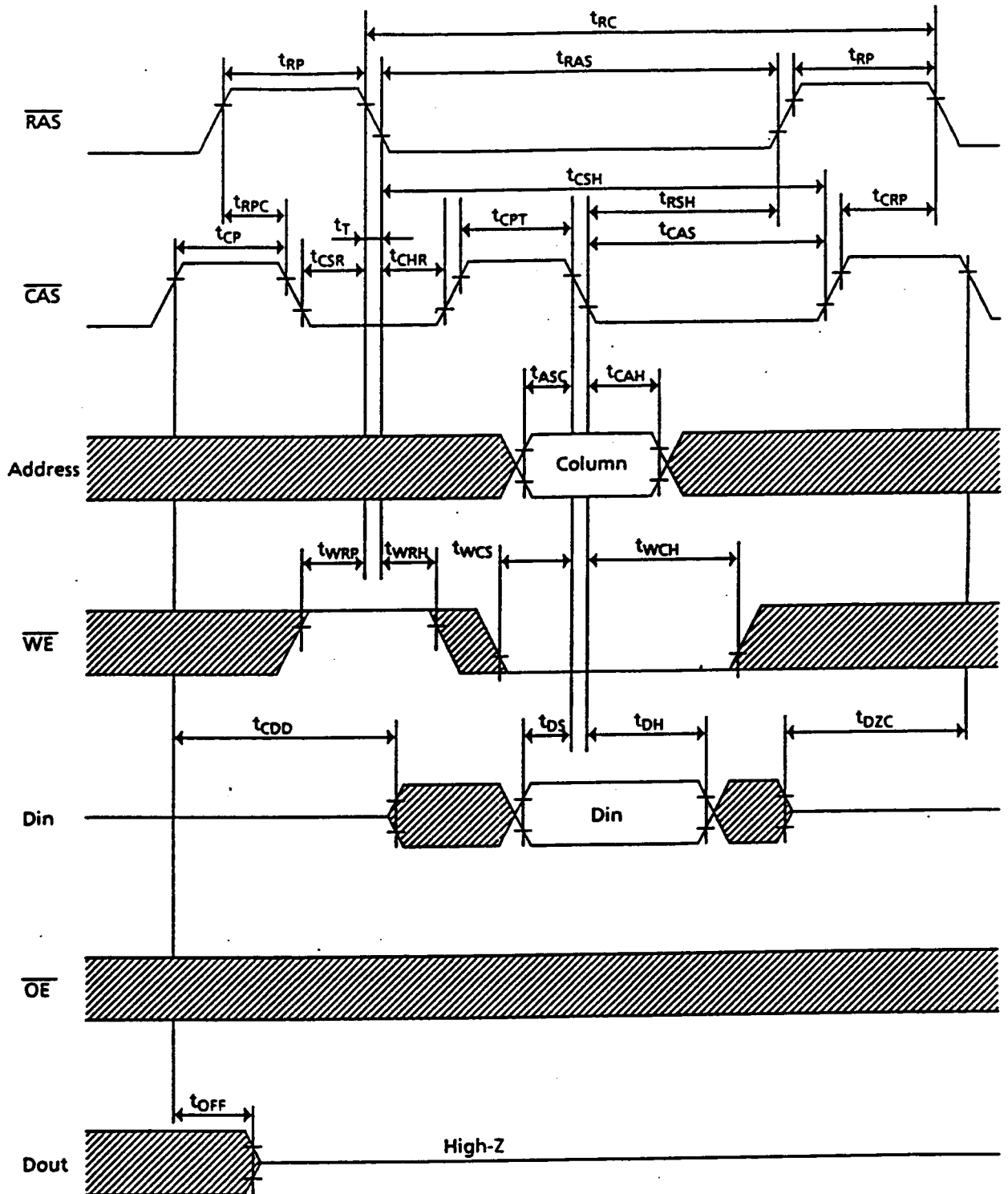
RAS-Only Refresh Cycle




$\overline{\text{CAS}}$ -Before- $\overline{\text{RAS}}$ Refresh Counter Check Cycle (Read)



CAS-Before-RAS Refresh Counter Check Cycle (Write)



•  : Don't care

NOTICE :

1. Hitachi, Ltd. reserves the right to make changes in its products without notice in order to improve reliability, function or design.
2. Information furnished herein by Hitachi, Ltd. has been carefully checked and is believed to be accurate and reliable. However, no responsibility is assumed by Hitachi, Ltd. for any damages by the use of information, products, or circuits herein ; nor for any infringements of patents or other rights of any party which may result from its use.
3. No license is granted by implication or otherwise under any patents or other rights of any third party or Hitachi, Ltd.
4. **MEDICAL APPLICATIONS :** Hitachi's products are not authorized for use in MEDICAL APPLICATIONS, including, but not limited to, use in life support devices without the written consent of the appropriate officer of Hitachi's sales company. Buyers of Hitachi's products are requested to notify Hitachi's sales offices when planning to use the products in MEDICAL APPLICATIONS.

Semiconductor & Integrated Circuits Div.
 New Marunouchi Bldg., 5-1, Marunouchi 1-chome, Chiyoda-ku, Tokyo, 100, Japan
 Tel : Tokyo (03) 212-1111
 Telex : J22395, J22432, J24491, J26375 (HITACHY)
 Fax : 03-214-3158 Cable : HITACHY TOKYO

For inquiry write to :

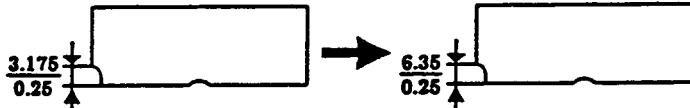
SAN JOSE
 Hitachi America, Ltd.
 Semiconductor & IC
 Division
 2210 O'Toole Ave., San Jose
 CA 95131, U.S.A.
 Tel : 408-435-8300
 Telex : 17-1581 (HITACHI SNJ)
 Twx : 910-338-2103
 Fax : 408-435-2748

MÜNCHEN
 Hitachi Europe GmbH
 Electronic Components Division
 Central European Headquarters
 Hans-Pinsel-Straße 10A,
 8013 Haar bei München,
 West Germany
 Tel : 089-4614-0
 Telex : 5-22593 (hitc d)
 Fax : 089-463068

LONDON
 Hitachi Europe Ltd.
 Electronic Components Division
 Northern Europe Headquarters
 21, Upton Road,
 Watford,
 Herts WD17TB, U.K.
 Tel : 0923-246488
 Telecom Gold : 265871 MONREF G
 ATTN 76 (HEC010)
 Telex : 936293 (HITEC G)
 Fax : 0923-224422

HONG KONG
 Hitachi Electronic Components
 (Asia), Ltd.
 Unit 512-513, 5/F North Tower
 World Finance Centre
 Harbour City, Canton Road, Tsim Sha Tsui
 Kowloon, Hong Kong
 Tel : 3-7219218-9, 7220698-9
 Telex : 40815 (HITEC HX)

■ Revision Record

Rev.	Date	Content of Modification	Drawn by	Approved by
0	Jun.03,'92	Initial issue	T.Sugano	K.Inoue
1	Nov.11,'91	Add presence detect pin for PD5 and PD6. Change of pin out for A10,A11 and PD2. Change of I _{CC7} Max. 850/750/700/650mA→750/650/550/500mA Change of t _{RWC} Min. 150/176/200/245ns→155/181/205/245ns Change of t _{RWD} Min. 80/93/105/135ns→85/98/110/135ns Change of t _{CWD} Min. 35/41/45/60ns→40/46/50/60ns Change of t _{AWD} Min. 50/58/65/80ns→55/63/70/80ns Change of t _{PRWC} Min. 80/91/100/110ns→85/96/105/120ns Change of t _{CPW} Min. 55/63/70/85ns→60/68/75/85ns Change of Hidden Refresh timing waveform.	T.Sugano	K.Inoue
2	May.22,'92	This specification is based on JEDEC standard for ×40. · Pin out Pin No.2 : DQ0 DQ0 Pin No.3 : DQ16 DQ1 Pin No.4 : DQ1 DQ2 Pin No.5 : DQ17 DQ3 Pin No.48 : V _{SS} →×40(V _{SS}) PD1-6→PD0-4 · Outline  Change of I _{CC7} Max. 750/650/550/500mA→950/850/800/750mA	J. Sugano	O. Sakai